

# Statistical Path Tracing in Timing Graphs

*Vasant Rao (IBM Poughkeepsie, NY)*

*Debjit Sinha (IBM Poughkeepsie, NY)*

*Nitin Srimal (IBM Bangalore, India)*

*Prabhat Maurya (IBM Bangalore, India)*

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# Background

- Path tracing is a key step in static timing analysis and optimization
  - Given a (set of) timing end-point(s) in a graph, trace backward and find a set of most critical paths leading to each end-point
  - Applications
    - Reporting (top N critical paths)
    - Common path pessimism reduction (CPPR)
    - Optimization of a set of most critical paths
- In a deterministic timing environment, backward path tracing is performed using notion of critical arrival time (AT)
  - In this case, path tracing using AT is equivalent to tracing using slack
- In a statistical timing environment, backward path tracing is not a simple extension of path tracing during deterministic timing
- Possible approaches to path tracing
  - **DPT**: (**D**eterministic **P**ath **T**racing) Based on deterministic AT or slack – **Incorrect** (example follows)
  - Based on statistical AT (projected, tightness-probability based, etc.) – **Incorrect** (example follows)
- Statistical required arrival time (RAT) has variability, plays a role in which path(s) are most critical (and at what corner)
- **SPT**: Statistical (slack based) Path Tracing is the correct way
  - However, how to rank order paths? Criticality – Definition?

# Linear Canonical Form (LCF)

\* courtesy Chandu Visweswariah (IBM Research)

$$a_0 + a_1 \Delta X_1 + a_2 \Delta X_2 + \dots + a_N \Delta X_N + a_R \Delta R$$

Mean  
(nominal  
value)

Sensitivities

Deviation of  
global sources  
of variation from  
their nominal  
values

Random  
uncertainty  
(deviation  
from nominal  
value)

- What does this canonical form have to do with statistical timing?
  - determining the  $a_1, a_2, \dots, a_N$  and  $a_R$  coefficients is sensitivity analysis
  - but if you think of  $\Delta X_1, \Delta X_2, \dots, \Delta X_N, \Delta R$  as random Gaussian variables, then this result is a statistical result (or linear regression) which can be plotted as a distribution

# LCF Math Operations

- Stat Add/Subtract
  - Mean and regular sensitivities are simply added/subtracted
  - Random sensitivity is always RSSed (root sum squared)
- Stat Min/Max
  - Clark's linear Gaussian approximation using tightness probabilities is used
  - Often introduces additional random term
- Projection: Get a number out of a Distribution (LCF)
  - Given corner  $c = \{c_1, c_2, \dots, c_N, c_R\}$
  - Define  $Proj_c(A) = a_0 + \sum_{i=1}^N a_i c_i + a_R c_R$
  - Often  $c_i = \{-3, +3\}$ . Also, sensitivities are usually RSSed to reduce pessimism.
- For simplicity, we will assume only simple LCFs in this paper.
  - All Timing quantities such as Delay, Arrival Time (AT), Slew, Required Arrival Time (RAT), and Slack will be assumed to be simple LCFs.

No guarantee of continuity in projected slack along a path

$$Proj(MIN(A, B)) \neq MIN(Proj(A), Proj(B))$$

$$Proj(MAX(A, B)) \neq MAX(Proj(A), Proj(B))$$

$$Slack = \begin{cases} RAT - AT & \text{if Late Mode} \\ AT - RAT & \text{if Early Mode} \end{cases}$$

Stat Math

# Late Mode Test Example

- Late Mode Stat Arrival Times:

$$AT_1 = 99 + 3.9V + 2.9T$$

$$AT_2 = 110 + 0.3V + 0.2T$$

Dropping  $\Delta$  in notation

$$AT_1 + d_1 = 100 + 4V + 3T$$

$$AT_2 + d_2 = 111 + 0.4V + 0.3T$$

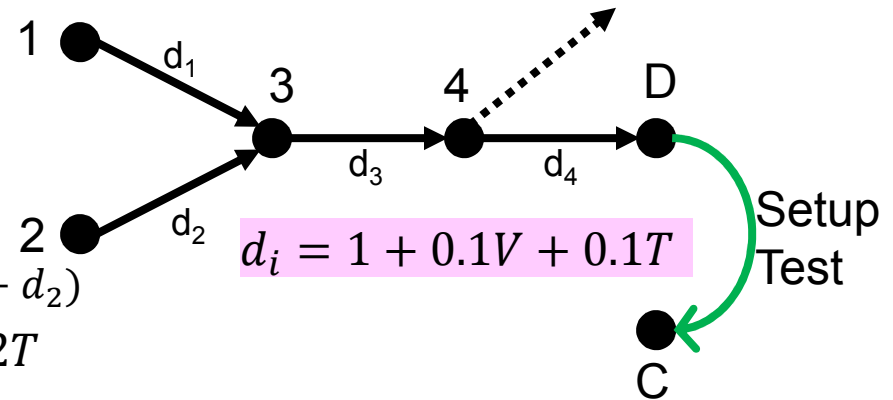
- Stat MAX at 3:  $AT_3 = \text{MAX}(AT_1 + d_1, AT_2 + d_2)$

$$AT_3 = 111.011 + 0.167R + 0.426V + 0.32T$$

- Tightness Probabilities:  $tp_1 = 0.007254, tp_2 = 0.992746$

➤ Closer to  $AT_2 + d_2$ . So, based on AT (Det. or Stat.), Node 2 is more "critical" than 1 feeding 3.

- Random appears in MAX even though incoming ATs had no random



$$d_i = 1 + 0.1V + 0.1T$$

- RAT on D:  $RAT_D = 112.523 + 0.6V + 0.5T$

- Back-propagate RAT from D to 3 (fanout at 4 does not contaminate RATs at either 4 or 3):

$$RAT_D - d_4 - d_3 = RAT_3 = 110.523 + 0.4V + 0.3T$$

- Slack = RAT - AT (random is RSSed; hence positive):

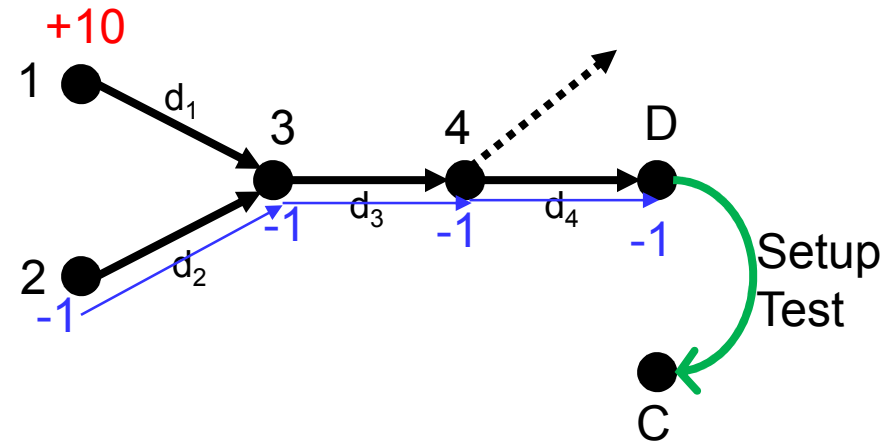
$$Slk_D = Slk_3 = -0.488 + 0.167R - 0.026V - 0.02T$$

$$Proj(Slk_D) = -0.488 - 3 \times \sqrt{(0.167)^2 + (-0.026)^2 + (-0.02)^2} = -1$$

Using RSS in Projection here

# DPT Method

- Work with Deterministic Numbers
  - Assume deterministic corner  $(V, T) = (0, 0)$
  - So, **deterministic = mean**
- Start at Data End of the Test (D) with projected Slack:  **$Proj(Slk_D) = -1$**
- Suppose CPPR cutoff = 0. So, start peeling paths for this test.



- Walk back to first “merge” point 3.
- Late Mode Incoming Deterministic Propagated ATs:

$$AT_1 + d_1 = 100 \quad \leftarrow \text{Diff} = 11 = 111 - 100$$

$$AT_2 + d_2 = 111 \quad \leftarrow \text{2 Wins}$$

- 2 wins because it has higher propagated AT.
  - Copy slack (-1) from 3 and back-propagate critical path to 2.
- Compute “slack” at 1 = sink\_slack + AT\_diff = -1 + 11 = **+10**
  - Would not schedule 1 for later peeling since it exceeds CPPR cutoff = 0.

## Problems with DPT:

1. Chooses 2 to be “critical” and assumes  $Proj(Slk_2) = -1$ . False slack continuity.
  - Will see this to be incorrect.
2. Does not schedule 1 for future peeling because it “thinks”  $Proj(Slk_1) = +10$ .
  - Will see this to be incorrect also.

# Proposed SPT Method

- Start at Data End of the Test (D) with projected Slack canonical

$$Proj(Slk_D) = -1$$

- Suppose CPPR cutoff = 0.
  - So, start peeling paths for this test.

- Walk back to first “merge” point 3.

- Compute Edge-Slacks:  $RAT_3 = 110.523 + 0.4V + 0.3T$

$$Slk_1 = RAT_3 - (AT_1 + d_1) = 10.523 - 3.6V - 2.7T; Proj(Slk_1) = -2.977 \leftarrow \text{Wins}$$

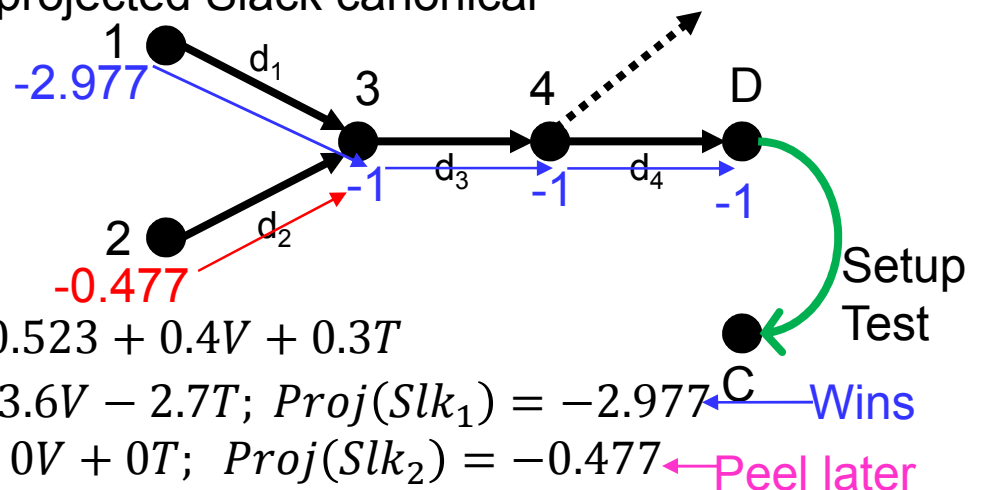
$$Slk_2 = RAT_3 - (AT_2 + d_2) = -0.477 + 0V + 0T; Proj(Slk_2) = -0.477 \leftarrow \text{Peel later}$$

- 1 wins because it has lower projected edge-slack = -2.977.
  - back-propagate critical path to 1.
- Schedule 2 for later peeling with projected edge-slack = -0.477 < 0.
- Note that DPT got both slacks at 1 and 2 wrong.
  - It picked the wrong winner (2). Even tightness probs on Stat MAX of ATs on node3 picks wrong winner (2).

- Also, no continuity in projected slack due to Stat MAX on ATs at node 3.

## SPT advantages:

- Chooses slack-critical inputs first at a merge point. Finds critical paths sooner.
- Computes correct path-slack canonical as it walks backwards.
  - Slack at the starting node of a peeled path is precisely the projection of the path-based slack canonical computed using path-based AT along that path.
- Makes CPPR check against “cutoff” more meaningful.



# Results

- **CPPR** (Common Path Pessimism Removal) implemented in a GBA (Graph or Block-Based Analysis) Statistical Timer
  - cutoff: Only analyze tests with original slack (OS) < specified value. Also, during path-tracing, schedule sub-critical inputs at a merge point with slack < specified value.
  - PPT (Paths Per Test): Stop further path peeling if number of paths currently peeled exceeds specified number.
  - Implemented both DPT and SPT as Path-tracing methods within CPPR.
- **Exhaustive CPPR**: unlimited cutoff and PPT.
  - Analyze all tests and peel all paths.
- **WS** (Worst Post-CPPR Slack) for a test.
- **WPI** (Worst Path Index): The path number at which WS was found for that test.
- **CPPR Safety**:  $PPT \geq \max WPI$  over all tests
  - smaller WPI is better since CPPR can be run with smaller PPT; hence faster.
- DPT vs SPT compare on 4 industrial designs (Exhaustive CPPR)

Design (# gates)	Number of Tests			
	Total	$WPI_{SPT} > WPI_{DPT}$	$WPI_{SPT} < WPI_{DPT}$	$WPI_{SPT} = WPI_{DPT}$
D1 (13K)	30K	12	2K	28K
D2 (0.5K)	2K	0	0.1K	1.9K
D3 (353K)	806K	451	64K	741K
D4 (12K)	25K	22	2K	23K

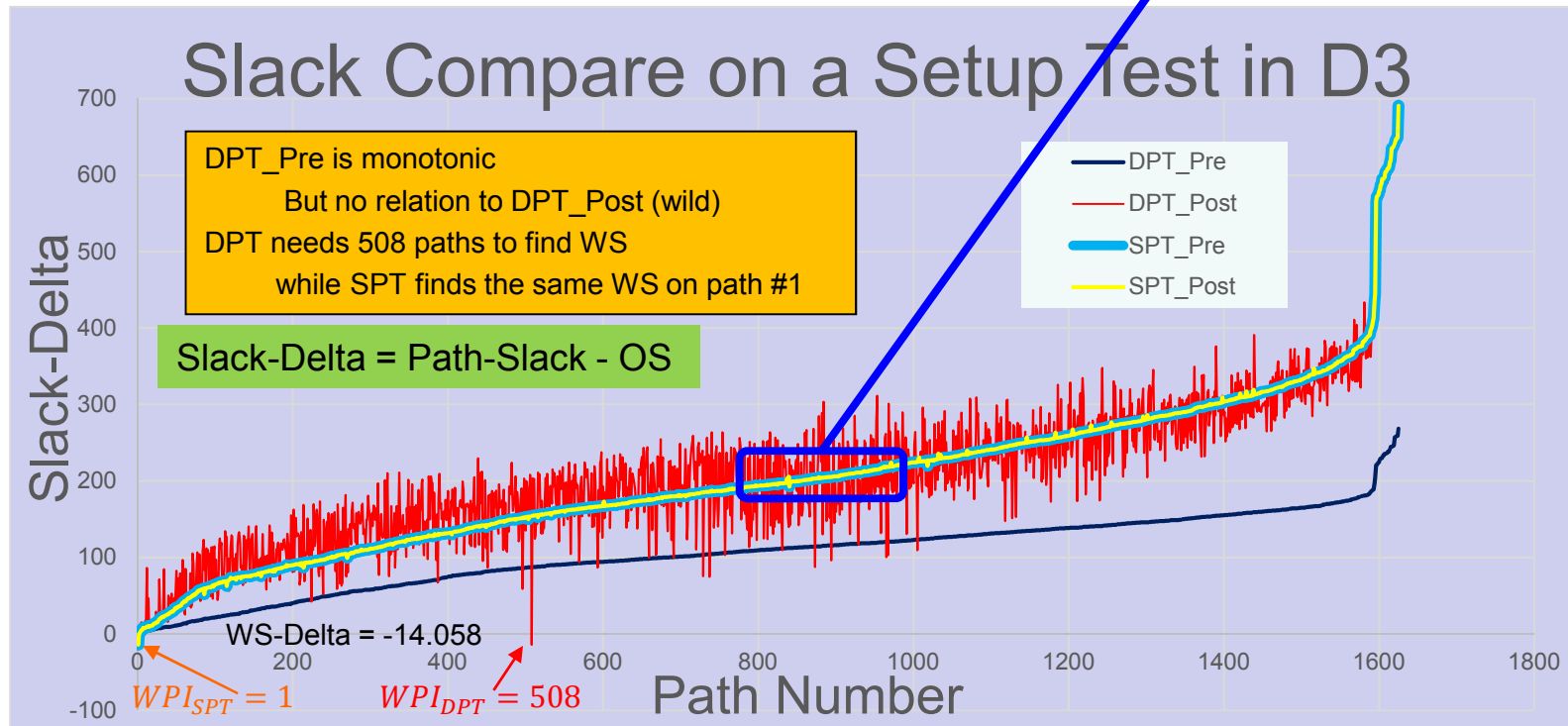
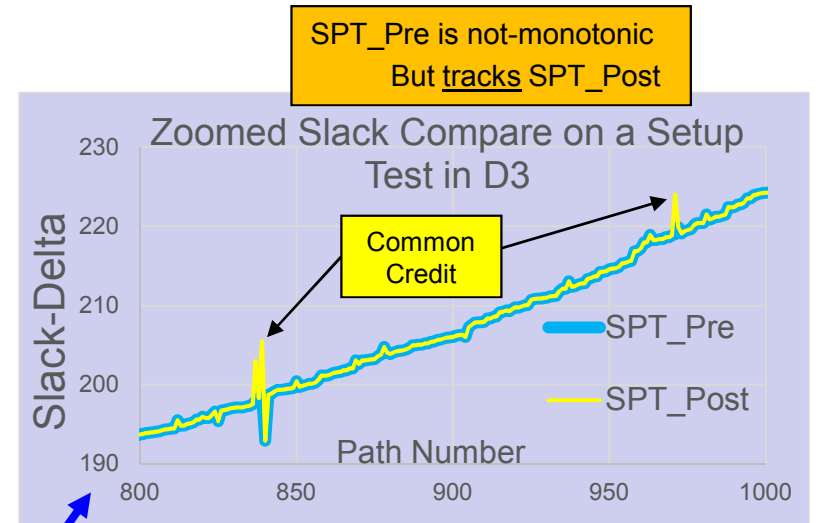
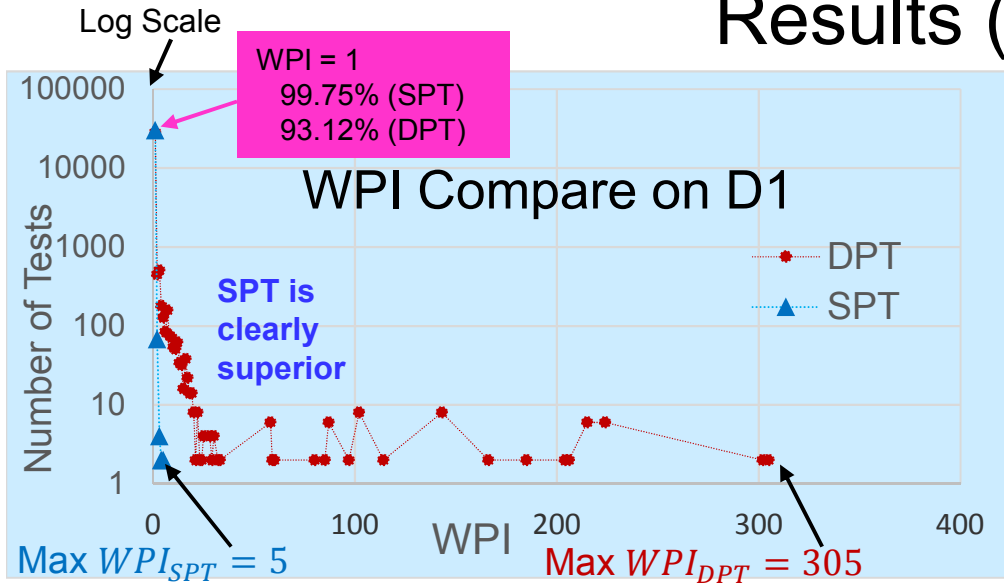
Max WPI-diff = 3

Design	Max $WPI_{DPT}$	Max $WPI_{SPT}$
D1	305	5
D2	4	1
D3	8364	31
D4	114	9

SPT is clearly superior



# Results (Contd.)



# Final Thoughts

1. SPT finds post-cppr critical paths sooner than DPT
  - SPT has smaller WPI
  - Can run CPPR with much smaller PPT; hence faster.
2. Running CPPR with cutoff = 10 on design D3
  - 99,889 tests were analyzed
  - 124 (i.e. 0.124%) of these showed  $WS_{DPT} > WS_{SPT}$ ; so CPPR with DPT is unsafe when run with a cutoff.
    - a. 9 of these were Setup Tests with diff  $WS_{DPT} - WS_{SPT} \in [13.038, 33.711]$  ps
    - b. 115 of these were Hold Tests with diff  $WS_{DPT} - WS_{SPT} \in [0.0037, 13.083]$  ps
  - DPT in all except 15 out of 124 of these tests peeled only 1 path because all sub-critical branches weren't scheduled for future peeling since their "pathSlack" exceeded the given cutoff value.
3. In Exhaustive CPPR, SPT is about 2X slower than DPT
  - Not surprising considering the extra stat calculations needed in SPT vs DPT
4. In a "Production" CPPR run on D3, SPT has been seen to be 30% faster than DPT due to much smaller PPT budget.
  - Much fewer paths peeled by SPT due to much smaller WPI.